## PRODUCTION AND ACCELERATION OF LIGHT— AND MEDIUM— HEAVY IONS AT THE JAERI TANDEM ACCELERATOR

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Four ions of  ${}^{10}$  B,  ${}^{27}$  Al,  ${}^{32}$ S and  ${}^{56}$ Fe have been successfully accelerated by the JAERI tandem accelerator. Negatively-charged atomic and molecular ions of these elements were obtained from a negative ion sputter source by using the cesium ionization gun developed in our laboratory. As details of the ion source

and the gun were already reported in the previous  $paper^{1),2)}$ , we do not explain them here.

Eleven sputtering cones were tested to know how much currents we can get from them, and how long they work. After this test, four cones of  $B,Al_2O_3$ , PbS

and  $Fe_{203}^{0}$  were selected to accelerate  ${}^{10}B$ ,  ${}^{27}A1$ ,  ${}^{32}S$  and  ${}^{56}Fe$  ions. Results of the

test are summarized in table 1. This table contains typical parameters of the ion source, negative ion currents and materials of the sputtering cones. Typical beam currents terminal voltage, beam energy, charge state and so on, are summarized in table 2. The beam currents were measured by electron-suppressed Faraday cups arranged along the beam lines. Locations of the Faraday cups are illustrated in fig.1.

Table.l Typical Parameters of the Ion Source, Negative Ion Currents and Ion Source Materials of the Sputtering Cones.

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Ion Source Material Abundance	В,	В,	Si+Al,	A1,	A1,	<sup>A1</sup> 2 <sup>0</sup> 3'	PbS,	Fe,	Fe <sub>2</sub> 0 <sub>3</sub> ,	Ge,	GeO 2
	10 92%	11 80%	27 100%	27 100%	27 100%	27 100%	32 95%	56 92%	56 92%	74 36%	74 36%
Beam Species & Currents(m icroampere)	10 <sub>B</sub> 1.67	11 <sub>B</sub> 0.01	Si+Al 3.13	A1 0.02	A1 0.09	A1 0.05	S 24.5	Fe 0.11	Fe 0.08	Ge 0.16	Ge 0.86
	10 <sub>BO</sub> 4.11	11 <sub>BO</sub> 0.19	SiO+A10 0.12	A10 0.10	A10 0.12	A10 1.31	SO 0.02	FeO 0.5	FeO 1.6	GeO 0.015	Ge0 0.01
Extraction Voltage(KV) Current(mA) Focus(-)(KV)	23 1.5 13 18 3	23 1.2 12.8 18 6	23 1.4 12.9 18.3	23 1.4 12.7 18.7	23 2.2 12.8 18.7	23 2.0 12.6 18.8	23 2.1 12.8 19.0	23 1.4 12.8 19.1	23 1.3 12.8 18.6	23 2.0 12.9 18.4	23 2.5 12.9 18.4
Supression Voltage(KV) X-Steerer(KV) Y-Steerer(KV) 0-Steerer(KV)	2.0 0.17 0.32 0.53	2.0 0.17 0.3 0.53	2.0 0.39 0.3 0.53	2.0 0.14 0.3 0.53	2.0 0.25 0.55 0.53	2.0 0.15 0.42 0.53	2.0 0.39 0.28 0.53	2.0 0.20 0.31 0.53	2.0 0.16 0.3 0.53	2.0 0.64 0.81 0.53	2.0 0.34 0.33 0.53
Ionizer Voltage(V) Current(A)	5.5 27	5.8 29	5.6 28	5.8 29	5.9 29	5.8 29	6.0 29	6.0 29	5.9 29	5.9 29	6.0 29
Oven Current(A)	0.19	0.16	0.20	0.18	0.22	0.19	0.18	0.19	0.19	0.22	0.23

Beam Species	10 <sub>B</sub>	27 <sub>A1</sub>	32 <sub>S</sub>	56 <sub>Fe</sub>	<sup>12</sup> C	16 <sub>0</sub>
Negative Ion Chemical Form	во	A10	• • • • • • •	FeO	С	0
Ion Source Materials	10 <sub>B</sub>	A12 <sup>0</sup> 3	PbS	Fe203	C	Ge02
Ion Source Terminal Voltage	NISS* 16.5	NISS 16.5	NISS 16.5	NISS 16.5	NISS 15.6	NISS 17.0
Beam Energy(MEV) Stripper Charge State Beam Currents,	72.3 foil 4+	126.1 foil 7+	181.7 foil 10+	178.1 foil 10+	93.8 foil 5+	119.3 foil 6+
/Faraday Cup FC I1-1	3.68 <sup>-6</sup>	3.75 <sup>-7</sup>	9.5 <sup>-7</sup>	3.13 <sup>-7</sup>	3.3 <sup>-6</sup>	3.4 <sup>-6</sup>
FC 02-1	3.36 <sup>-6</sup>	3.68 <sup>-7</sup>	8.04 <sup>-7</sup>	3.55 <sup>-7</sup>	2.2 <sup>-6</sup>	2.3 <sup>-6</sup>
FC TH-1	6.71 <sup>-7</sup>	2.38 <sup>-7</sup>	6.95 <sup>-7</sup>	1.24 <sup>-7</sup>	3.24 <sup>-6</sup>	2.2 <sup>-6</sup>
FC 04-1	3.02 <sup>-7</sup>	1.26 <sup>-7</sup>	9.8 <sup>-7</sup>	1.81 <sup>-7</sup>	3.0 <sup>-6</sup>	2.2 <sup>-6</sup>
Target	1	/	1	1	3.0 <sup>-6</sup>	2.2 <sup>-6</sup>

\* Negative Ion Sputter Source

References

1) E.Minehara, S.Abe, C.Kobayashi and S.Kikuchi., Proc. 4th Symp. on Ion Sources and Ion Application Technology, p261(1980).

2) S.Abe, E.Minehara, C.Kobayashi and S.Kikuchi., Proc. 6th Symp. on Ion Sources and Ion-Assisted Technology, p185(1982).

Fig.1 Faraday Cups arranged along the beam lines of the JAERI Tandem Accelerator



Table 2 Beam Currents and Other Parameters of the Accelerator.